2024년 1월 **24**일(수)-**26**일(금) | 경주화백컨벤션센터(HICO)

2024년 1월 25일(목), 10:55-12:40 Room I(203),2층

D. Thin Film Process Technology 분과 [TI2-D] Memory Capacitors

좌장: 전우진 교수(경희대학교), 이홍섭 교수(경희대학교)

	소성: 신우신 교수(경의대학교), 이용섭 교수(경의대학교)
	High-Performance Nanostructured Flexible Capacitor by Plasma-
초청발표	Assisted Atomic Layer Annealing at Low Temperature
TI2-D-1	Jaehyeong Lee ¹ , Dohyun Go ¹ , Useng Lee ¹ , Jong. G Ok ¹ , and Jihwan An ²
10:55-11:25	¹ Department of Manufacturing Systems and Design Engineering, SeoulTech,
	² Department of Mechanical Engineering, POSTECH
TI2-D-2 11:25-11:40	Low Temperature Crystallization of Atomic Layer Deposited SrTiO ₃
	Films with Minimal Interfacial Reactions
	Hong Keun Chung ^{1,2} , Tae Joo Park ² , and Seong Keun Kim ^{1,3}
	¹ Electronic Materials Research Center, KIST, ² Department of Materials Science and
	Chemical Engineering, Hanyang University, ³ KU-KIST Graduate School of
	Converging Science and Technology, Korea University
TI2-D-3 11:40-11:55	Improvement of Electrical Properties of ZrO ₂ /Al ₂ O ₃ Capacitors via
	Interfacial Defect Control Using Ar Plasma Treatment
	Hyeongjun Kim and Woongkyu Lee
	Department of Green Chemistry and Materials Engineering and Department of
	Materials Science and Engineering, Soongsil University
TI2-D-4 11:55-12:10	The Precise Control of the Interfacial Reactions in TiO ₂ /RuO ₂ -
	structured Capacitors for DRAM Applications
	Jihoon Jeon ^{1,2} , Taikyu Kim ¹ , Myungsu Jang ^{1,2} , Hong Keun Chung ¹ , and Seong
	Keun Kim ^{1,2}
	¹ Electronic Materials Research Center, KIST, ² KU-KIST Graduate School of
	Converging Science and Technology, Korea University
TI2-D-5 12:10-12:25	Fabrication of MoO ₂ Electrode by Thermal Atomic Layer Deposition for
	High-performance TiO ₂ -Based DRAM Capacitors
	Jae Hyeon Lee, Wangu Kang, Jeong Eun Shin, and Jeong Hwan Han
	Department of Materials Science and Engineering, Seoul National University of
	Science and Technology

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	Plasma-enhanced Atomic Layer Deposition of TiN/Mo₂N Stacks for
TI2-D-6	Advanced Storage Nodes in Next-generation DRAM Capacitors
12:25-12:40	Wangu Kang, Ji Sang Ahn, Ha Young Lee, Byung Joon Choi, and Jeong Hwan Han
	Department of Materials Science and Engineering, Seoultech